

1. General description

Planar passivated Silicon Controlled Rectifier (SCR) in a SOT78 (TO-220AB) plastic package intended for use in applications requiring very high bidirectional blocking voltage capability, high junction temperature capability and high thermal cycling performance.

2. Features and benefits

- High junction operating temperature capability
- High thermal cycling performance
- Planar passivated for voltage ruggedness and reliability
- Very high bidirectional blocking voltage capability

3. Applications

- Capacitive Discharge Ignition (CDI)
- Crowbar protection
- Inrush protection
- Motor control
- Voltage regulation

4. Quick reference data

Table 1. Qu	uick reference data		 			
Symbol	Parameter	Conditions	Min	Тур	Мах	Unit
V _{DRM}	repetitive peak off- state voltage		-	-	1000	V
V _{RRM}	repetitive peak reverse voltage		-	-	1000	V
I _{TSM}	non-repetitive peak on- state current	half sine wave; $T_{j(init)} = 25 \text{ °C};$ $t_p = 10 \text{ ms}; \text{ Fig. 4}; \text{ Fig. 5}$	-	-	120	A
Tj	junction temperature		-	-	150	°C
I _{T(RMS)}	RMS on-state current	half sine wave; T _{mb} ≤ 134 °C; <u>Fig. 1;</u> <u>Fig. 2; Fig. 3</u>	-	-	12	A
Static charac	cteristics					
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u>	-	2	15	mA





5. Pinning information

Table 2.	Pinning	information		
Pin	Symbol	Description	Simplified outline	Graphic symbol
1	К	cathode	mb	A -₽+ K
2	А	anode	$2 \rightarrow 0$	G sym037
3	G	gate		
mb	A	mounting base; connected to anode		
			TO-220AB (SOT78)	

6. Ordering information

Table 3. Ordering information								
Type number	Package							
	Name	Description	Version					
BT151-1000RT	TO-220AB	plastic single-ended package; heatsink mounted; 1 mounting hole; 3-lead TO-220AB	SOT78					

7. Limiting values

Table 4. Limiting values

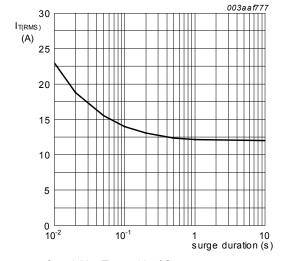
In accordance with the Absolute Maximum Rating System (IEC 60134).

Parameter	Conditions	Min	Max	Unit
repetitive peak off-state voltage		-	1000	V
repetitive peak reverse voltage		-	1000	V
average on-state current	half sine wave; $T_{mb} \le 134 \text{ °C}$	-	7.5	А
RMS on-state current	half sine wave; T _{mb} ≤ 134 °C; <u>Fig. 1;</u> <u>Fig. 2; Fig. 3</u>	-	12	A
non-repetitive peak on-state current	half sine wave; $T_{j(init)} = 25 \text{ °C};$ $t_p = 10 \text{ ms}; \frac{\text{Fig. 4}}{2}; \frac{\text{Fig. 5}}{2}$	-	120	A
	half sine wave; $T_{j(init)}$ = 25 °C; t_p = 8.3 ms	-	132	A
I ² t for fusing	t _p = 10 ms; SIN	-	72	A ² s
rate of rise of on-state current	I_T = 20 A; I_G = 50 mA; dI_G/dt = 50 mA/ μs	-	50	A/µs
peak gate current		_	2	А
	repetitive peak off-state voltage repetitive peak reverse voltage average on-state current RMS on-state current non-repetitive peak on-state current l	repetitive peak off-state voltagerepetitive peak reverse voltageaverage on-state currenthalf sine wave; $T_{mb} \le 134 ^{\circ}C$ RMS on-state currenthalf sine wave; $T_{mb} \le 134 ^{\circ}C$; Fig. 1; Fig. 2; Fig. 3non-repetitive peak on-state currentnon-repetitive peak on-state currenthalf sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 10 $ ms; Fig. 4; Fig. 5half sine wave; $T_{j(init)} = 25 ^{\circ}C$; $t_p = 8.3 $ msl^2t for fusingrate of rise of on-state currentI_T = 20 A; I_G = 50 mA; dI_G/dt = 50 mA/ µs	repetitive peak off-state voltage-repetitive peak reverse voltage-average on-state currenthalf sine wave; $T_{mb} \le 134 \ ^{\circ}C$ -RMS on-state currenthalf sine wave; $T_{mb} \le 134 \ ^{\circ}C$; Fig. 1; Fig. 2; Fig. 3-non-repetitive peak on-state currenthalf sine wave; $T_{mb} \le 134 \ ^{\circ}C$; Fig. 1; Fig. 2; Fig. 3-non-repetitive peak on-state currenthalf sine wave; $T_{j(init)} = 25 \ ^{\circ}C$; $t_p = 10 \ ms; Fig. 4; Fig. 5-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;t_p = 8.3 \ ms-laft sine wave; T_{j(init)} = 25 \ ^{\circ}C;T_{j(init)} = 25 \ ^{\circ}C;$	repetitive peak off-state voltage-1000repetitive peak reverse voltage-1000average on-state currenthalf sine wave; $T_{mb} \le 134$ °C-7.5RMS on-state currenthalf sine wave; $T_{mb} \le 134$ °C; Fig. 1; Fig. 2; Fig. 3-12non-repetitive peak on-state currenthalf sine wave; $T_{j(init)} = 25$ °C; $t_p = 10$ ms; Fig. 4; Fig. 5-120if the function of

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Symbol	Parameter	Conditions	Min	Max	Unit
V _{RGM}	peak reverse gate voltage		-	5	V
P _{GM}	peak gate power		-	5	W
P _{G(AV)}	average gate power	over any 20 ms period	-	0.5	W
T _{stg}	storage temperature		-40	150	°C
Tj	junction temperature		-	150	°C



f = 50 Hz; T_{mb} = 134 $^{\circ}$ C

Fig. 1. RMS on-state current as a function of surge duration; maximum values

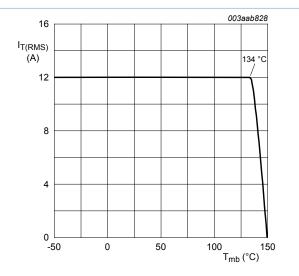
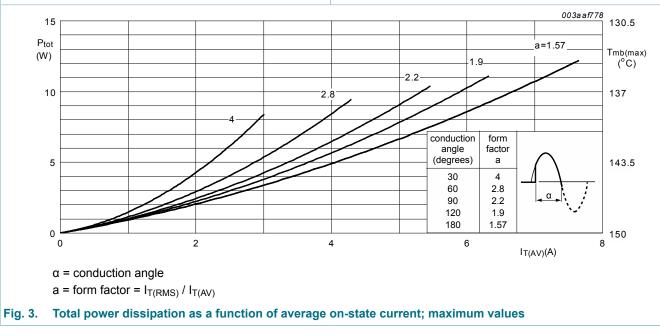
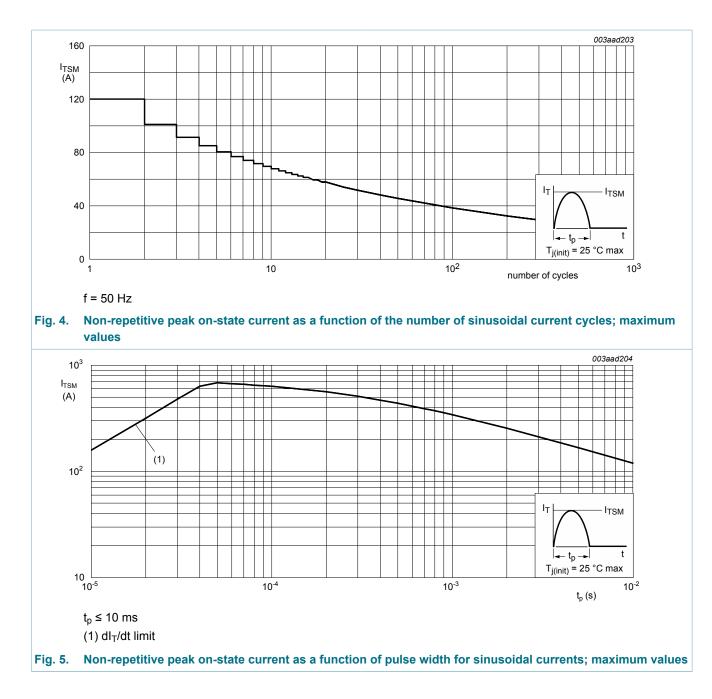


Fig. 2. RMS on-state current as a function of mounting base temperature; maximum values



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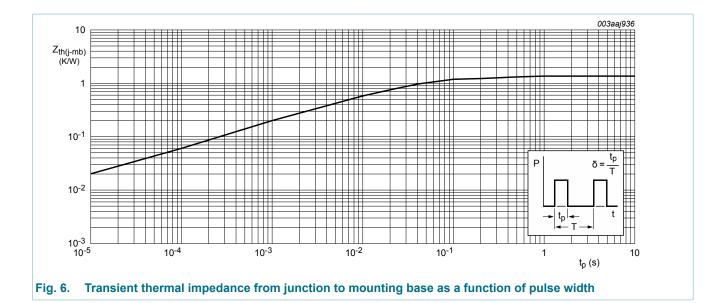


Thermal characteristics 8.

Table 5.	The	rmal characteristics						
Symbol		Parameter	Conditions		Min	Тур	Max	Unit
R _{th(j-mb)}		thermal resistance from junction to mounting base	<u>Fig. 6</u>		-	-	1.3	K/W
R _{th(j-a)}		thermal resistance from junction to ambient	in free air		-	60	-	K/W
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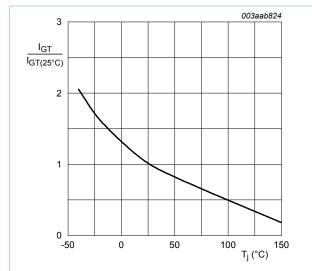


9. Characteristics

Symbol	Parameter	Conditions	Min	Тур	Max	Unit
Static char	acteristics	I I				
I _{GT}	gate trigger current	V _D = 12 V; I _T = 0.1 A; T _j = 25 °C; <u>Fig. 7</u>	-	2	15	mA
IL	latching current	V_D = 12 V; I _G = 0.1 A; T _j = 25 °C; <u>Fig. 8</u>	-	10	40	mA
I _H	holding current	V _D = 12 V; T _j = 25 °C; <u>Fig. 9</u>	-	7	20	mA
V _T	on-state voltage	I _T = 23 A; T _j = 25 °C; <u>Fig. 10</u>	-	1.4	1.75	V
V _{GT}	gate trigger voltage	$V_D = 12 V; I_T = 0.1 A; T_j = 25 °C;$ Fig. 11	-	0.6	1	V
		V _D = 1000 V; I _T = 0.1 A; T _j = 150 °C; Fig. 11	0.25	0.4	-	V
I _D	off-state current	V _D = 1000 V; T _j = 150 °C	-	0.5	2.5	mA
I _R	reverse current	V _R = 1000 V; T _j = 150 °C	-	0.5	2.5	mA
Dynamic cl	haracteristics	· · · · · ·				
dV _D /dt	rate of rise of off-state voltage	V_{DM} = 670 V; T _j = 150 °C; (V _{DM} = 67% of V _{DRM}); exponential waveform; gate open circuit; Fig. 12	-	300	-	V/µs
t _{gt}	gate-controlled turn-on time	$I_{TM} = 40 \text{ A}; \text{ V}_{D} = 1000 \text{ V}; \text{ I}_{G} = 0.1 \text{ A}; \\ d\text{I}_{G}/dt = 5 \text{ A}/\mu\text{s}; \text{ T}_{j} = 25 ^{\circ}\text{C}$	-	2	-	μs
tq	commutated turn-off time	$\begin{split} & V_{DM} = 670 \; V; \; T_{j} = 150 \;^{\circ}C; \; I_{TM} = 20 \; A; \\ & V_{R} = 25 \; V; \; (dI_{T}/dt)_{M} = 30 \; A/\mus; \; dV_{D}/ \\ & dt = 50 \; V/\mus; \; R_{GK} = 100 \; \Omega; \; (V_{DM} = 67\% \\ & of \; V_{DRM}) \end{split}$	-	70	-	μs

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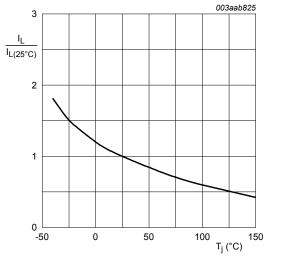


Fig. 7. Normalized gate trigger current as a function of Junction temperature

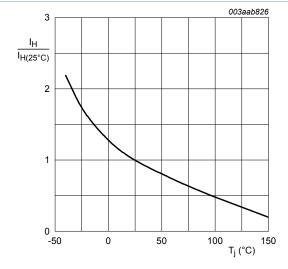
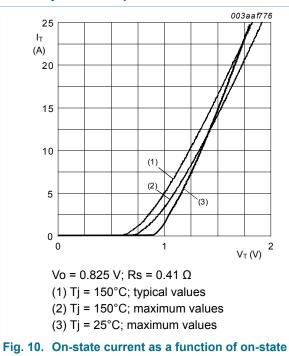


Fig. 9. Normalized holding current as a function of junction temperature

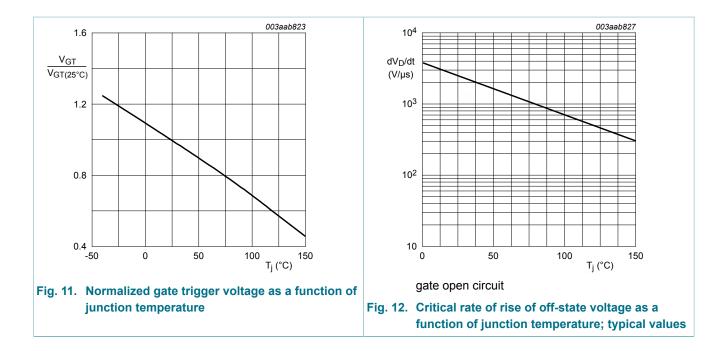
8. Normalized latching current as a function of junction temperature



voltage

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10. Package outline

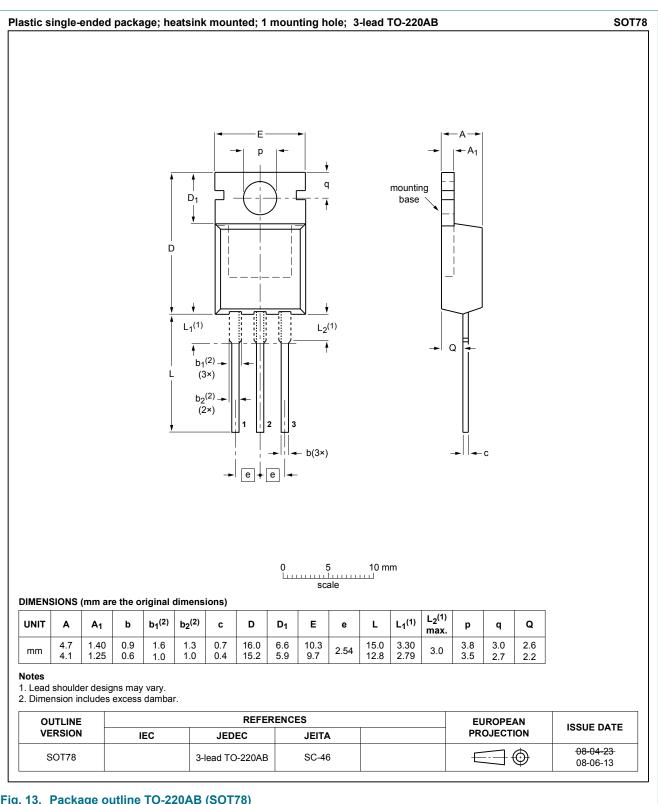


Fig. 13. Package outline TO-220AB (SOT78)

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